

# **N-Channel Enhancement Mode Field Effect Transistor**

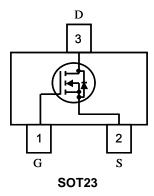
### Features

Advanced trench process technology
High-density cell design for ultra low on-resistance
Compact and low profile SOT23 package

#### General Description

This N-Channel enhancement mode power FETs are produced with high cell density, DMOS trench technology, which is especially used to minimize on-state resistance. This device is particularly suited for low voltage application such as portable equipment, power management and other battery powered circuits, and low in-line power dissipation are needed in a very small outline surface mount package. Excellent thermal and electrical capabilities.

## • Pin Configurations



# Absolute Maximum Ratings @T<sub>A</sub>=25℃ unless otherwise noted

Parameter		Symbol	Ratings	Unit	
Drain-Source Voltage		V <sub>DSS</sub>	200	V	
Gate-Source Voltage		V <sub>GSS</sub>	±20	V	
Drain Current (1)(2)	Continuous		2.0	А	
	Pulsed	l <sub>D</sub>	6		
Power Dissipation		P <sub>D</sub>	150	mW	
Operating and Storage Junction Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C	

# • Electrical Characteristics @T<sub>A</sub>=25°C unless otherwise noted

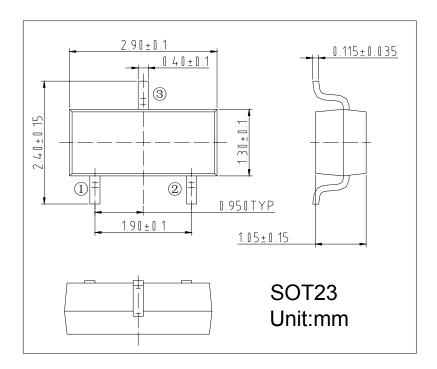
Symbol	Parameter	Limit	Min	Тур	Max	Unit			
STATIC									
VDS	Drain-Source Breakdown Voltage	VGS=0V, ID=250μA	200			V			
VGS(th)	Gate Threshold Voltage	VDS=VGS, ID=250μA	1.0		3.0	٧			
IGSS	Gate Leakage Current	VDS=0V, VGS=±20V			±100	nA			
IDSS	Zero Gate Voltage Drain Current	VDS=60V, VGS=0V			1	μА			
RDS(ON)	Daria Carras Ca Basistanas	VGS=10V, ID= 2.0A		520	580	- mΩ			
	Drain-Source On-Resistancea	VGS=4.5V, ID= 1.5A		650	800				
VSD	Diode Forward Voltage	IS=1A, VGS=0V		0.8	1.2	V			
DYNAMIC		·	•			<u>,                                      </u>			
Qg	Total Gate Charge	VDS=30V, VGS=10V, ID=2.0A	VDS=30V, VGS=10V, ID=2.0A 12						
Qg	Total Gate Charge			6.5		nC			
Qgs	Gate-Source Charge	VDS=30V, VGS=4.5V, ID=2.0A		2.2					
Qgd	Gate-Drain Charge			2.7					
Ciss	Input capacitance			350		pF			
Coss	Output Capacitance	VDS=30V, VGS=0V, f=1.0MHz		40					
Crss	Reverse Transfer Capacitance			12					
Rg	Gate Resistance	VDS=0V, VGS=0V, f=1MHz		0.7		Ω			
td(on)	Turn-On Delay Time			10		ns			
tr	Turn-On Rise Time	VDD=20V, RL =20Ω ID=1A,		11					
td(off)	Turn-Off Delay Time	VGEN=10V RG=1Ω		29					
tf	Turn-Off Fall Time			3					

### Notes:

(1). Pulse Test : Pulse Width  $< 300 \mu s$ , Duty Cycle < 2%.

(2). Surface Mounted on FR4 Board, t < 10 sec.

## Package Information



## IMPORTANT NOTICE

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